

High Speed Wafer Screening system

Cosmo Finder

This is a new Wafer Inspection System that realizes the inspection with high speed and high resolution based on the microscope.

➤ Features

1. High-speed inspection

Tact time for 6" Wafer : 10min
@5x objective, Minimum resolution : 0.69 μ m

2. High Versatility

Capable of viewing the wafer map and registration of image processing parameters.

3. Automatic Alignment

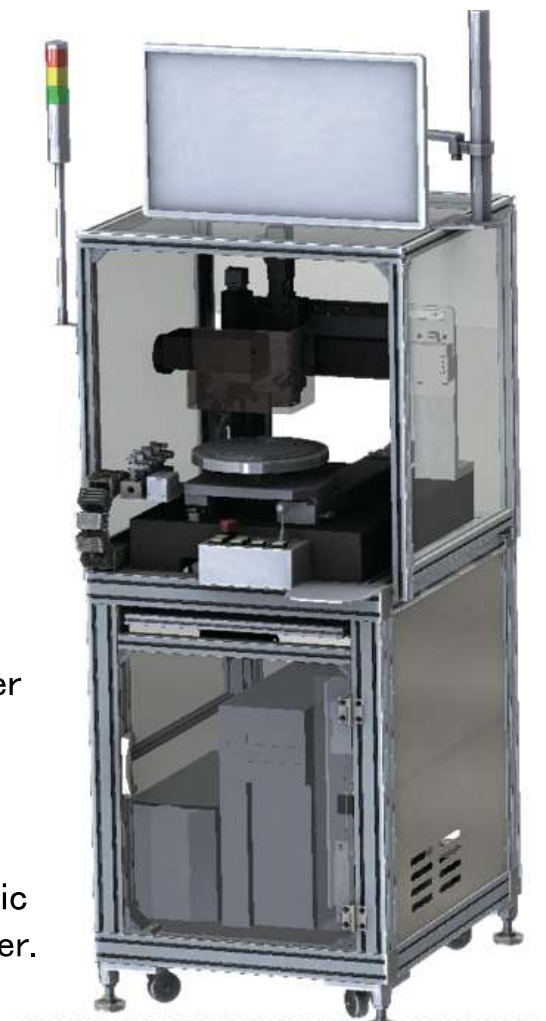
Error is reduced by automatic alignment with X, Y and θ .

4. Customizable

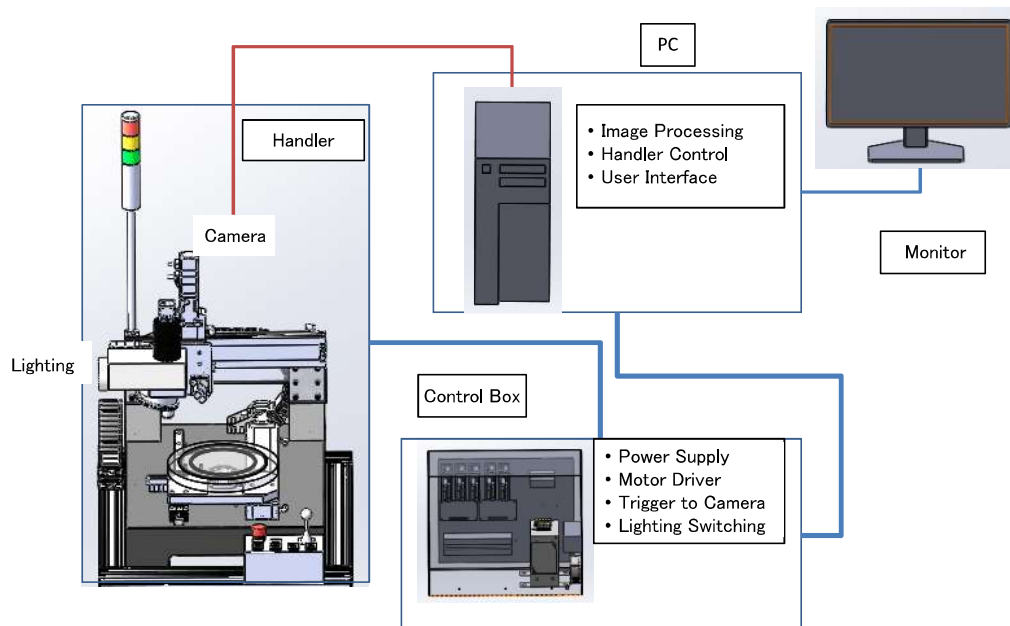
Capable of customizing depending on the wafer size, objective magnification and so on.

5. Linking with Wafer loader

Capable of extending to the cassette automatic inspection system with linking with wafer loader.



System Configuration




Specifications

| Items | Specification |
|--|---|
| Camera ※Specification changeable | |
| Type | 5M pixels画素CMOS Camera(2448 × 2048Pixel) |
| Sensor size | 2/3" (8.4 × 7mm) |
| Frame rate | 25FPS |
| Optical System ※Magnification changeable | |
| Objective | 5x, WD : 20mm, NA : 0.15 |
| Camera adoptor | 0.5x |
| Field of View | 3.4 × 2.8mm @ 5x |
| Pixel resolution | 1.38 μm/Pixel @ 5x |
| Lighting | Coaxial episcopic illumination |
| Light source | White LED |
| Stage ※Size changeable | |
| Travel of X-axis | 250mm |
| Travel of Y-axis | 350mm |
| Travel of Z-axis | 50mm |
| Moving speed of X and Y | MAX 100mm/sec |
| Repeatability of X, Y and Z | ±0.02mm |
| Angle range of θ-axis | ±10° |
| Repeatability of θ | ±0.004° |
| AF | |
| Method | Triangulation using laser light |
| Detection accuracy | ±1 μm |
| Interval | 1 time per 1 device |
| AF time | less than 100msec(except the exposure time) |

*Please understand that the product name, specifications and model number may be changed without a notice.

● Developer

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